Sintering and compositional effects on the microwave dielectric characteristics of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics with $0.25 \le x \le 0.35$

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Abstract 1,500 °C-sintered MgTa₂O₆ ceramic exhibits microwave dielectric characteristics of $\varepsilon_r = 30.5$, $Q \times f =$ 56,900 GHz, and τ_f =28.3 ppm/°C, whereas 1,400 °Csintered MgNb₂O₆ ceramic exhibits microwave dielectric characteristics of ε_r =21.7, $Q \times f$ =89,900 GHz, and τ_f = -68.5 ppm/°C. In order to find the dielectric resonators with $\tau_{\rm f}$ value close to 0 ppm/°C, the effects of sintering condition and composition on the microwave dielectric characteristics of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics $(0.25 \le x \le$ 0.35) prepared under sintering temperature of 1,300-1,450 °C are investigated. The results show that as the sintering temperature increases from 1,300 to 1,450 °C, the ε_r , $Q \times f$ and τ_f values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics all increase and saturate at 1,450 °C. On the other hand, as the Nb₂O₅ content decreases, the τ_f values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics will shift to near 0 ppm/°C. The optimized sintering conditions and composition to obtain the Mg(Ta_{1-x}Nb_x)₂O₆ dielectrics with $\tau_{\rm f}$ close to 0 ppm/°C are sintering temperature of 1,450 °C, sintering duration of 4 h, and composition of x=0.25, which exhibits the microwave

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C.-C. Chan Department of Biochemical Engineering, Kao Yuan Institute of Technology, Kaohsiung, Taiwan, Republic of China dielectric characteristics of ε_r =27.9, $Q \times f$ =33,100 GHz, and τ_f =-0.7 ppm/°C.

Keywords $Mg(Ta_{1-x}Nb_x)_2O_6 \cdot Microwave characteristics \cdot Orthorhombic$

1 Introduction

High quality AB₂O₆ (A=Ca, Mg, Mn, Co, Ni, Zn and B= Nb, Ta) compounds had been investigated as microwave dielectric resonators by Lee et al. [1] and Kan et al. [2]. Lee et al. reported that MgNb₂O₆ sintered at 1,300 °C exhibited relative dielectric constant (ε_r) of 21.4, quality factor ($Q \times f$) of 93,800 GHz, and temperature coefficient of resonant frequency ($\tau_{\rm f}$) of -70 ppm/°C and MgTa₂O₆ sintered at 1,550 °C exhibited ε_r =30.3, $Q \times f = 59,600$ GHz, and τ_f = 30 ppm/°C. Both had high $Q \times f$ values and dielectric constants of higher than 20, but both also revealed large $\tau_{\rm f}$ values. To adjust $\tau_{\rm f}$ value of microwave dielectric resonators close to 0 ppm/°C, two or more compounds having negative and positive $\tau_{\rm f}$ values are employed to form a solid solution or mixed phases in order to obtain the desired $\tau_{\rm f}$ values. Kucheiko reported that zero $\tau_{\rm f}$ value could be achieved in CaTiO₃-Ca(Al_{1/2}Ta_{1/2})O₃ system [3]. Chen et al. reported that small $\tau_{\rm f}$ value was achieved in CaO-Li₂O-Sm₂O₃-TiO₂ (CLST) system [4], in which the $Li_{1/2}Sm_{1/2}TiO_3$ ($\varepsilon_r=52$, $Q \times f = 2,280$ GHz, and $\tau_f = -260$ ppm/°C) and CaTiO₃ $(\varepsilon_r = 170, Q \times f = 3,600 \text{ GHz}, \text{ and } \tau_f = 800 \text{ ppm/°C})$ dielectrics were employed [5].

The substitution of similar ions in dielectric resonators can improve the microwave dielectric characteristics. For example, in the BiNbO₄ system, Nd₂O₃ and Sm₂O₃ can be used to substitute Bi₂O₃ to form (Bi_{1-x}Nd_x)NbO₄ and (Bi_{1-x}Sm_x) NbO₄ compositions [6, 7], Ta₂O₅ can be used to substitute Nb₂O₅ to form Bi(Nb_{1-x}Ta_x)O₄ compositions [8], and all the three compositions possess high $Q \times f$ and low $\tau_{\rm f}$ values. In the BaSm₂Ti₄O₁₂ system, SrO and Nd₂O₃ can be used to substitute BaO and Sm₂O₃ to form (Ba,Sr)Sm₂Ti₄O₁₂ and Ba(Sm,Nd)₂Ti₄O₁₂ compositions [4,9], and the microwave dielectric characteristics can also be improved, especially, the $\tau_{\rm f}$ values can be adjusted to near 0 ppm/°C.

In our preliminary study, MgTa₂O₆ ceramics sintered at 1,500 °C exhibited the microwave dielectric characteristics of τ_f =28.3 ppm/°C, ε_r =30.5 and $Q \times f$ = 56,900 GHz, whereas MgNb₂O₆ ceramics sintered at 1,400 °C exhibited the microwave dielectric characteristics of $\tau_{\rm f}$ =-68.5 ppm/°C, $\varepsilon_r = 21.7$, and $Q \times f = 89,900$ GHz, as shown in Table 1. In order to obtain the microwave dielectrics with $\tau_{\rm f}$ close to 0 ppm/°C, the compositions of Mg(Ta_{1-x}Nb_x)₂O₆ were investigated in this study. The empirical method was adopted to combine the microwave dielectric characteristics of MgTa₂O₆ (with positive τ_f) and MgNb₂O₆ (with negative $\tau_{\rm f}$), and the results showed that the zero $\tau_{\rm f}$ value would exist within the range of $0.25 \le x \le 0.35$. As a result, the compositions of Mg(Ta_{1-x}Nb_x)₂O₆ (0.25 $\leq x \leq 0.35$) were developed and their sintering behaviors and microwave dielectric characteristics were investigated.

2 Experimental

Proportional amounts of reagent-grade starting materials of MgO, Ta₂O₅, and Nb₂O₅ were mixed according to the compositions of Mg(Ta_{1-x}Nb_x)₂O₆, (x=0.25, 0.3, and 0.35, abbreviated as MTN1, MTN2, and MTN3, respectively), and ball-milled for 5 h with deionized water. After drying, the powder was ground and calcined at 1,100 °C for 2 h. After mixing with polyvinyl alcohol (PVA) as binder, the mixed powder was pressed into pellets in a steel die. After debindering, sintering of these pellets was carried out at temperature between 1,300 and 1,450 °C under ambient conditions for 4 h.

Table 1 The microwave dielectric properties of $MgTa_2O_6$ and $MgNb_2O_6$ ceramics.

Material	Sintering temperature (°C)	$\boldsymbol{\varepsilon}_{\mathrm{r}}$	$Q \times f$ (GHz)	τ _f (ppm/°C)
MgTa ₂ O ₆	1,400	25.2	28,500	22.4
	1,450	28.9	44,300	27.1
	1,500	30.5	56,900	28.3
	1,550	30.6	58,200	28.5
MgNb ₂ O ₆	1,300	15.7	34,100	-78.0
	1,350	20.5	66,500	-69.1
	1,400	21.7	89,900	-68.5
	1,450	21.8	91,500	-68.3

The crystal structures were analyzed by means of X-ray powder diffraction method using CuK_{α} radiation (Rigaku D-max/IIB). The densities of sintered specimens, as a function of sintering temperature, were measured by the liquid displacement method using deionized water as the liquid (Archimedes's method). To investigate the morphologies of the samples, the surfaces of sintered specimens were observed by SEM (Hitachi S-2500). Dielectric characteristics at microwave frequency were measured by Hakki and Coleman's dielectric resonator method [10], which was improved by Courtney [11]. An HP8720ET network analyzer was used for the measurements of microwave dielectric characteristics. The dielectric constant can be accurately determined by measuring the resonant frequency of the TE₀₁₁ mode and verified by the TE_{01 δ} resonant modes. The temperature variation of resonant frequency $\Delta f_0/f_0$ and the temperature coefficient of resonant frequency $\tau_{\rm f}$ are defined as:

$$\Delta f_0 / f_0 = (f_T - f_0) / f_0 \tag{1}$$

and

$$\tau_f = \Delta f_0 / (f_0 \times \Delta T) \tag{2}$$

where f_T and f_0 are the resonant frequencies at 85 and 25°C, respectively, and ΔT is 60°C.

3 Results and discussion

Typical X-ray diffraction patterns of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics are shown in Fig. 1. MgTa₂O₆ ceramic exists a single phase with tetragonal structure, whereas, MgNb₂O₆ ceramic exists a single phase with orthorhombic structure. The results show that the lattice constants of MgNb₂O₆ ceramic sintered at 1,300°C are a=5.720 Å, b=5.306 Å, and c=14.1780 Å. On the other hand, MgTa₂O₆ ceramics sintered at 1,500 °C exhibit the lattice constants of a=b=4.7173 Å and c=9.2094 Å. The Mg(Ta_{1-x}Nb_x)₂O₆ ceramics have the crystal structure of orthorhombic, which is similar to that of MgNb₂O₆ ceramic; however, their lattice constants are smaller than those of MgNb₂O₆ ceramic. In our previous report, the Mg(Ta_{1-x}Nb_x)₂O₆ ceramics were revealed to exist a phase transition within x=0.1-0.2 from tetragonal to orthorhombic phase [12], hence, no tetragonal phase appeared in Fig. 1 with $0.25 \le x \le 0.35$. The results also show that as the Nb₂O₅ content increases form x=0.25to x=0.35, the lattice constants of a, b, and c slightly increase from 5.484 Å, 4.998 Å, and 13.724 Å to 5.507 Å, 5.109 Å, and 13.948 Å, which is due to the smaller ionic radius of Ta⁵⁺ (0.64 Å) than that of Nb⁵⁺ (0.69 Å).

The variations in the morphologies of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics under different sintering temperatures and compositions can be observed by SEM photographs. The changes

Fig. 1 The X-ray patterns of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics sintered at different temperatures



in density and grain size of selected Mg(Ta_{1-x}Nb_x)₂O₆ ceramics are shown in Fig. 2. For 1,300 °C-sintered Mg(Ta₁ $_{-x}Nb_x)_2O_6$ ceramics, isolated Mg(Ta_{1-x}Nb_x)₂O₆ grains and pores can be revealed, as shown in Fig. 2a. Further increasing of sintering temperature to 1,350 °C, homogeneous fine microstructures with fewer pores are observed, which is shown in Fig. 2b. The pores of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics decrease and the grain sizes increase with the increase of sintering temperature, which are independent of Nb₂O₅ content. As sintered at 1,400 °C, the grain sizes are enlarged for samples with larger Nb₂O₅ content, this result is obvious by comparing the Fig. 2c, d, and e. This appears that the grain growth is improved due to the increase of sinterability induced by the Nb₂O₅ substitution.

The ε_r values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics were measured as functions of sintering temperature and composition, and the results are shown in Fig. 3. The ε_r values of all Mg(Ta_{1-x}Nb_x)₂O₆ ceramics increased with sintering temperature and saturated at about 1,400 °C, independent of the Nb₂O₅ content. The relationships between ε_r values and sintering temperature revealed the same trend with those between densities and sintering temperatures since higher sintering temperature caused grain growth and fewer pores. The saturated ε_r values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics linearly decrease from 27.94 to 26.2 as x varied from 0.25 to 0.35. This result implies that the effect of Nb₂O₅ substitution on the ε_r values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics is apparent.

Figure 4 shows the $Q \times f$ values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics as functions of sintering temperature and composition. As sintering temperature increases, the $Q \times f$ values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics increase and then reach the saturation values at 1,400 °C. The increase in grain growth and decrease in pores may cause this result. In the Mg(Ta_{1-x}Nb_x)₂O₆ system, even the dielectric constant decreases with the increase of Nb₂O₅ content, the $Q \times f$

Fig. 2 The microstructures of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics sintered at, **a** 1,300 °C, and **b** 1,350 °C for x=0.35, and sintered at 1,400 °C for **c** x= 0.25, **d** x=0.3, and **e** x=0.35



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Fig. 3 The dielectric constants of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics as a function of sintering temperature

value increases apparently with the increase of Nb₂O₅ content. For Mg(Ta_{1-x}Nb_x)₂O₆ ceramics sintered at 1,400 °C, the $Q \times f$ values increase from 29,500 for x=0.25 to 40,100 for *x*=0.35.

The τ_f values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics with various Nb₂O₅ content at different sintering temperatures are demonstrated in Fig. 5. Both Nb₂O₅ content and sintering temperature have large influences on the $\tau_{\rm f}$ values of Mg $(Ta_{1-x}Nb_x)_2O_6$ ceramics. For the sintering temperature ranged 1,300–1,450 °C, the $\tau_{\rm f}$ values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics vary from a larger negative value to a smaller negative one, which may due to the decreased pores in Mg



Fig. 4 The quality values of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics as a function of sintering temperature

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Fig. 5 The temperature coefficient of resonant frequency of Mg $(Ta_{1-x}Nb_x)_2O_6$ ceramics as a function of sintering temperature

 $(Ta_{1-x}Nb_x)_2O_6$ ceramics as sintered at higher temperature. In essence, the temperature coefficient of resonant frequency $\tau_{\rm f}$ of a dielectric is a function of the thermal expansion coefficient (α) and the temperature coefficient of dielectric constant (τ_{ε}) , that is $\tau_{\rm f} \cong -(\alpha + \frac{1}{2}\tau_{\varepsilon})$, which is revealed to be a negative value for air [13]. Because the air is enclosed in the pores, the $\tau_{\rm f}$ value will vary steadily from a larger negative value to a smaller negative one as the pores decrease with the increased sintering temperature for Mg $(Ta_{1-x}Nb_x)_2O_6$ ceramics. On the other hand, as the Nb₂O₅ content decreases, the τ_f values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics will also shift to near 0 ppm/°C. The results show that the saturated $\tau_{\rm f}$ values for MTN3, MTN2, and MTN1 ceramics sintered at 1,450 °C are -4.1 ppm/°C, -2.8 ppm/°C,

Table 2 The microwave dielectric properties of $Mg(Ta_{1-x}Nb_x)_2O_6$ ceramics.

Material	Sintering temperature (°C)	$\boldsymbol{\varepsilon}_{\mathrm{r}}$	$Q \times f$ (GHz)	τ _f (ppm/°C)
MgTa _{1.5} Nb _{0.5} O ₆	1,300	21.8	12,100	-4.8
(MTN1, x=0.25)	1,350	26.2	23,500	-1.7
	1,400	27.7	29,500	-0.9
	1,450	27.9	33,100	-0.7
MgTa _{1.4} Nb _{0.6} O ₆	1,300	21.7	14,300	-5.2
(MTN2, <i>x</i> =0.3)	1,350	25.5	27,100	-3.0
	1,400	27.0	37,400	-2.8
	1,450	27.3	40,800	-2.8
MgTa _{1.3} Nb _{0.7} O ₆	1,300	20.4	16,100	-6.2
(MTN3, <i>x</i> =0.35)	1,350	24.5	29,400	-4.4
	1,400	26.1	40,100	-4.2
	1,450	26.2	43,100	-4.1

and -0.7 ppm/°C, respectively. Finally, all the microwave dielectric characteristics for various Mg(Ta_{1x}Nb_x)₂O₆ compositions and sintering temperatures are listed in Table 2. The optimized sintering conditions and composition to obtain the Mg(Ta_{1-x}Nb_x)₂O₆ dielectrics with $\tau_{\rm f}$ close to 0 ppm/°C are sintering temperature of 1,450 °C, sintering duration of 4 h, and composition of x=0.25, which exhibits the microwave dielectric characteristics of $\varepsilon_{\rm r}$ =27.9, $Q \times f$ = 33,100 GHz, and $\tau_{\rm f}$ =-0.7 ppm/°C.

4 Conclusion

The sintering behaviors and microwave dielectric characteristics of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics ($0.25 \le x \le 0.35$) are influenced by the sintering temperature and Nb₂O₅ content, including grain growth, dielectric constant, quality factor, and τ_f value. In this system, the dielectric constant increases, the quality factor decreases, and the τ_f value shift to near 0 ppm/°C as the Nb₂O₅ content decreases. However, the saturated τ_f values of Mg(Ta_{1-x}Nb_x)₂O₆ ceramics ($0.25 \le x \le 0.35$) are all within the range of -4.1--0.7 ppm/°C, which indicates that the Mg(Ta_{1-x}Nb_x)₂O₆ system is available to be adopted as microwave dielectric resonators. In this report, the optimized sintering conditions and composition to obtain the Mg(Ta_{1-x}Nb_x)₂O₆ dielectrics with τ_f close to 0 ppm/°C are sintering temperature of 1,450 °C, sintering duration of 4 h, and composition of x=0.25, which exhibits the microwave dielectric characteristics of $\varepsilon_r=27.9$, $Q \times f = 33,100$ GHz, and $\tau_f=-0.7$ ppm/°C.

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